



# ACE8212B

## Common Drain N-Channel Enhancement Mode Field Effect Transistor with ESD

### Description

The ACE8212B uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. They offer operation over a wide gate drive range from 1.8V to 12V. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

### Features

- $V_{DS}(V)=20V$
- $I_D=8A$  ( $V_{GS}=10V$ )
- TSSOP-8  
 $R_{DS(ON)}<13\text{ m}\Omega$  ( $V_{GS}=10V$ )  
 $R_{DS(ON)}<14\text{ m}\Omega$  ( $V_{GS}=4.5V$ )  
 $R_{DS(ON)}<19\text{ m}\Omega$  ( $V_{GS}=2.5V$ )  
 $R_{DS(ON)}<27\text{ m}\Omega$  ( $V_{GS}=1.8V$ )
- DFN2\*5  
 $R_{DS(ON)}<13\text{ m}\Omega$  ( $V_{GS}=10V$ )  
 $R_{DS(ON)}<16\text{ m}\Omega$  ( $V_{GS}=4.5V$ )  
 $R_{DS(ON)}<22\text{ m}\Omega$  ( $V_{GS}=2.5V$ )  
 $R_{DS(ON)}<35\text{ m}\Omega$  ( $V_{GS}=1.8V$ )
- ESD Protected: 2000V

### Absolute Maximum Ratings

Parameter			Symbol	Max	Unit
Drain-Source Voltage			V <sub>DSS</sub>	20	V
Gate-Source Voltage			V <sub>GSS</sub>	±12	V
Continuous Drain Current *AC	T <sub>A</sub> =25°C		I <sub>D</sub>	8	A
	T <sub>A</sub> =70°C			6.4	
Pulsed Drain Current			I <sub>DM</sub>	30	A
Power Dissipation	TSSOP-8	T <sub>A</sub> =25°C	P <sub>D</sub>	1.5	W
		T <sub>A</sub> =70°C		1	
	DFN2*5	T <sub>A</sub> =25°C		1.6	
		T <sub>A</sub> =70°C		1	
Operating Junction Temperature / Storage Temperature Range			T <sub>J</sub> /T <sub>STG</sub>	-55/150	°C

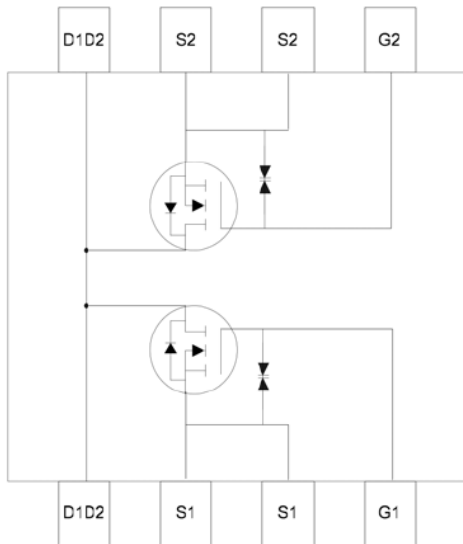


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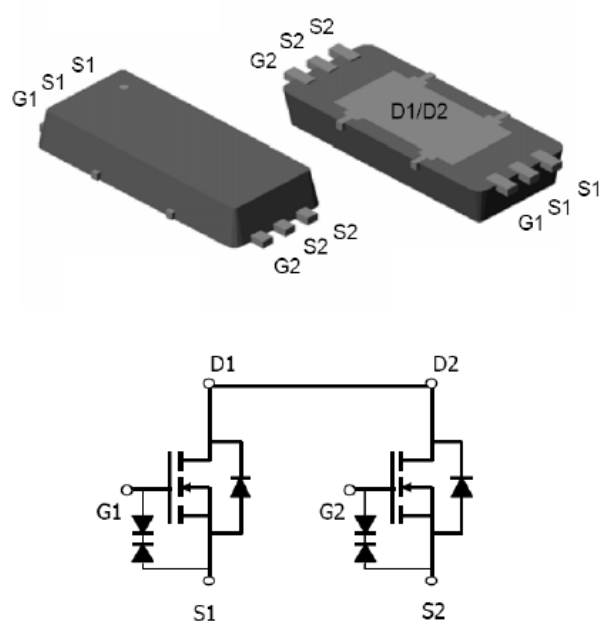
Common Drain N-Channel Enhancement Mode Field Effect Transistor with ESD

## Packaging Type

TSSOP-8



DFN2\*5



## Ordering information

ACE8212B XX + H

- └─ Halogen - free
- └─ Pb - free
- └─ TM : TSSOP-8
- └─ JN : DFN2\*5



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## Common Drain N-Channel Enhancement Mode Field Effect Transistor with ESD

### Electrical Characteristics

$T_A=25^{\circ}\text{C}$ , unless otherwise noted.

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250 uA	20			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	0.5	0.72	1	
Gate Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±12V			10	uA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V			1	uA
Maximum Body-Diode Continuous Current	I <sub>S</sub>				2.4	A
Drain-Source On-Resistance (TSSOP-8)	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =8A		8.2	13	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A		9.2	14	
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =4A		12	19	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =3A		18	27	
Drain-Source On-Resistance (DFN2*5)	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =8A		10	13	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =7A		11	16	
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =6A		14	22	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =4.5A		21	35	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =8A		30		S
Diode Forward Voltage	V <sub>SD</sub>	I <sub>SD</sub> =1A, V <sub>GS</sub> =0V		0.72	1.0	V
Switching						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A		4.65	6.05	nC
Gate-Source Charge	Q <sub>gs</sub>			1.12	1.46	
Gate-Drain Charge	Q <sub>gd</sub>			3.72	4.84	
Turn-On Time	td(on)	V <sub>GS</sub> =10V, R <sub>L</sub> =10Ω, V <sub>DS</sub> =10V, R <sub>GEN</sub> =3Ω		487.6	975.2	ns
	tr			800.4	1600.8	
Turn-Off Time	td(off)			1728	3456	
	tf			6180	12360	
Dynamic						
Input Capacitance	Ciss	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, f=1MHz		36.45		pF
Output Capacitance	Coss			183.88		
REVERSE Transfer Capacitance	Crss			14.57		



Note:

1. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design.
2. Repetitive rating, pulse width limited by junction temperature.
3. The current rating is based on the  $\leq 10\text{s}$  junction to ambient thermal resistance rating.

### Typical Performance Characteristics

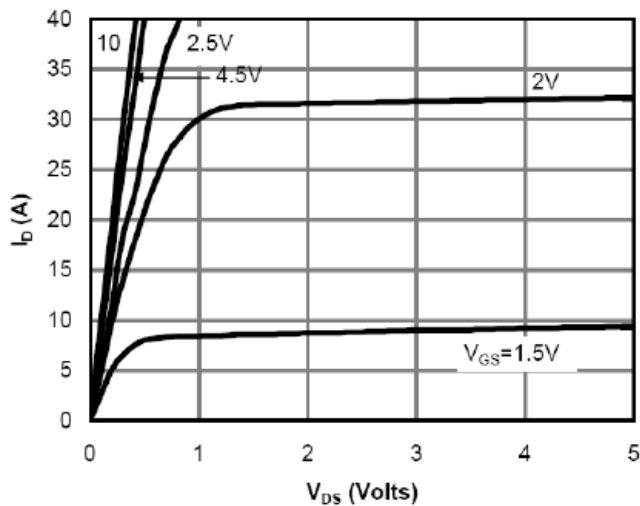


Fig 1: On-Region Characteristics

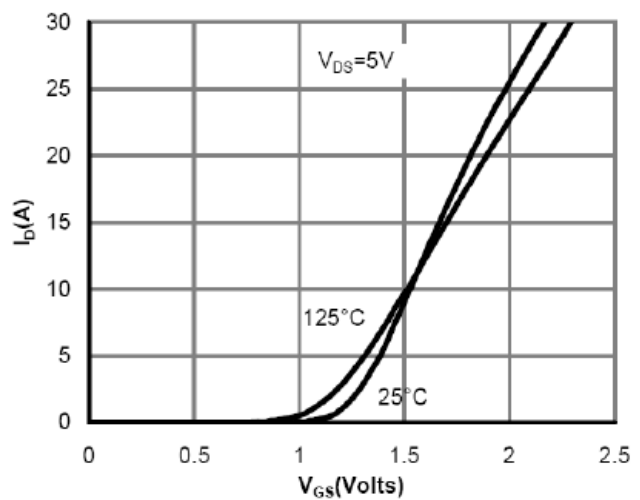


Figure 2: Transfer Characteristics

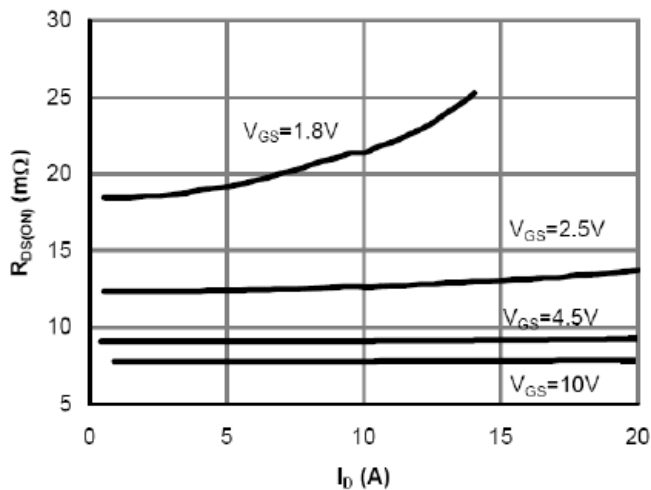


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

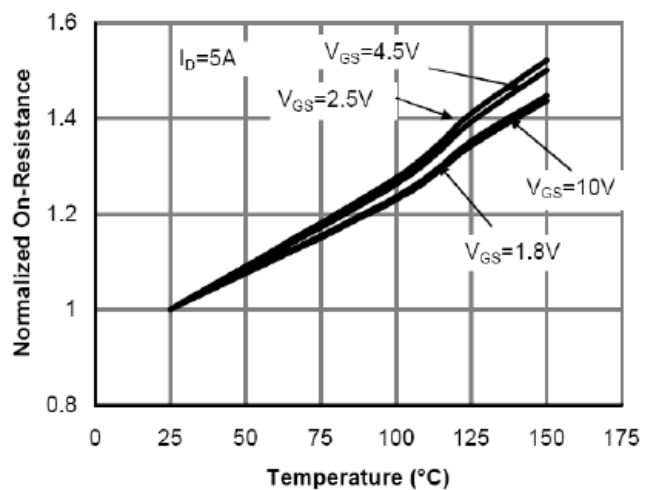


Figure 4: On-Resistance vs. Junction Temperature



### Typical Performance Characteristics

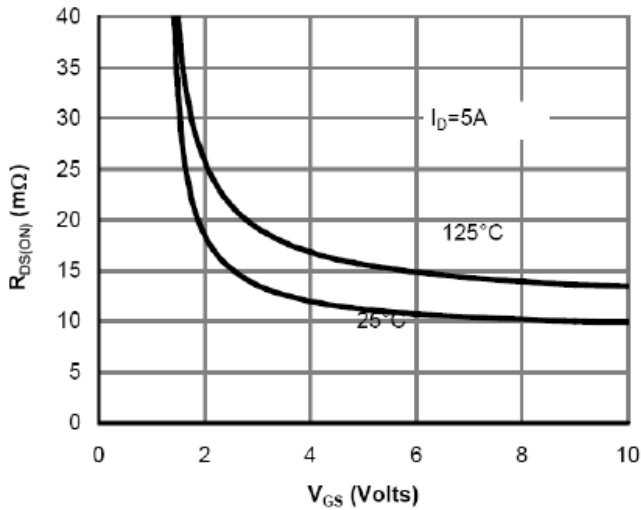


Figure 5: On-Resistance vs. Gate-Source Voltage

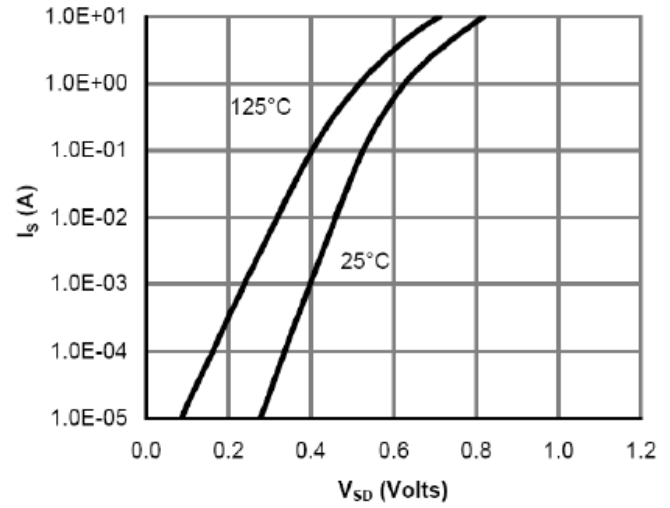


Figure 6: Body-Diode Characteristics

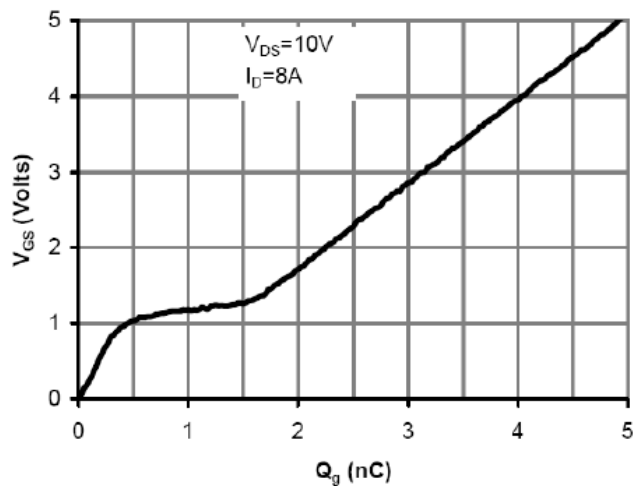


Figure 7: Gate-Charge Characteristics

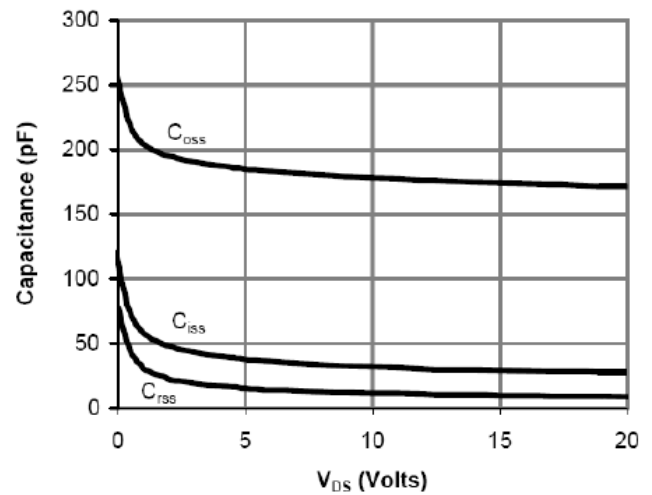


Figure 8: Capacitance Characteristics

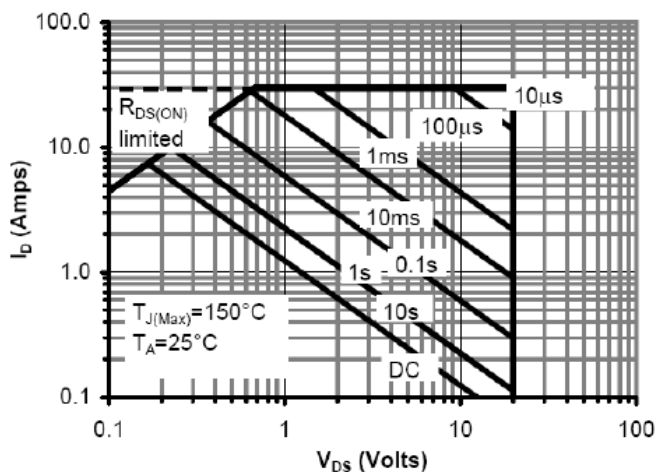


Figure 9: Maximum Forward Biased Safe Operating Area

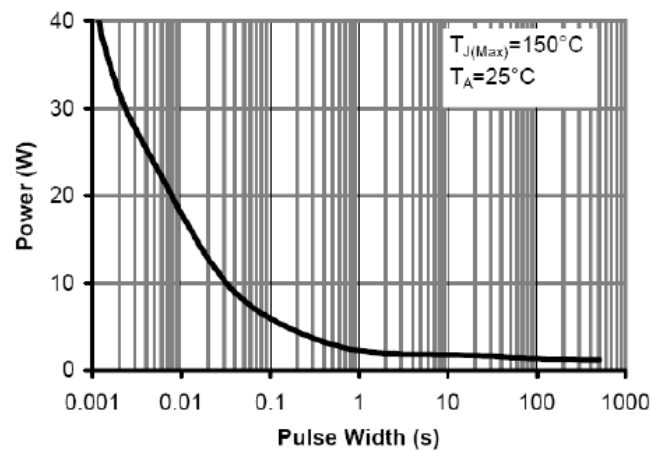


Figure 10: Single Pulse Power Rating Junction-to-Ambient



### Typical Performance Characteristics

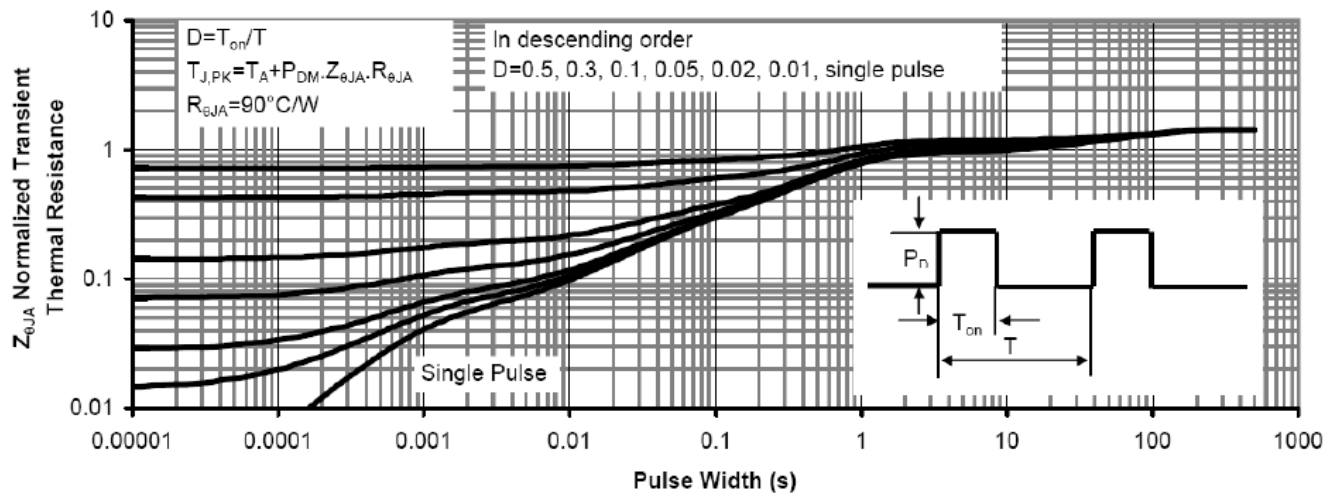


Figure 11: Normalized Maximum Transient Thermal Impedance

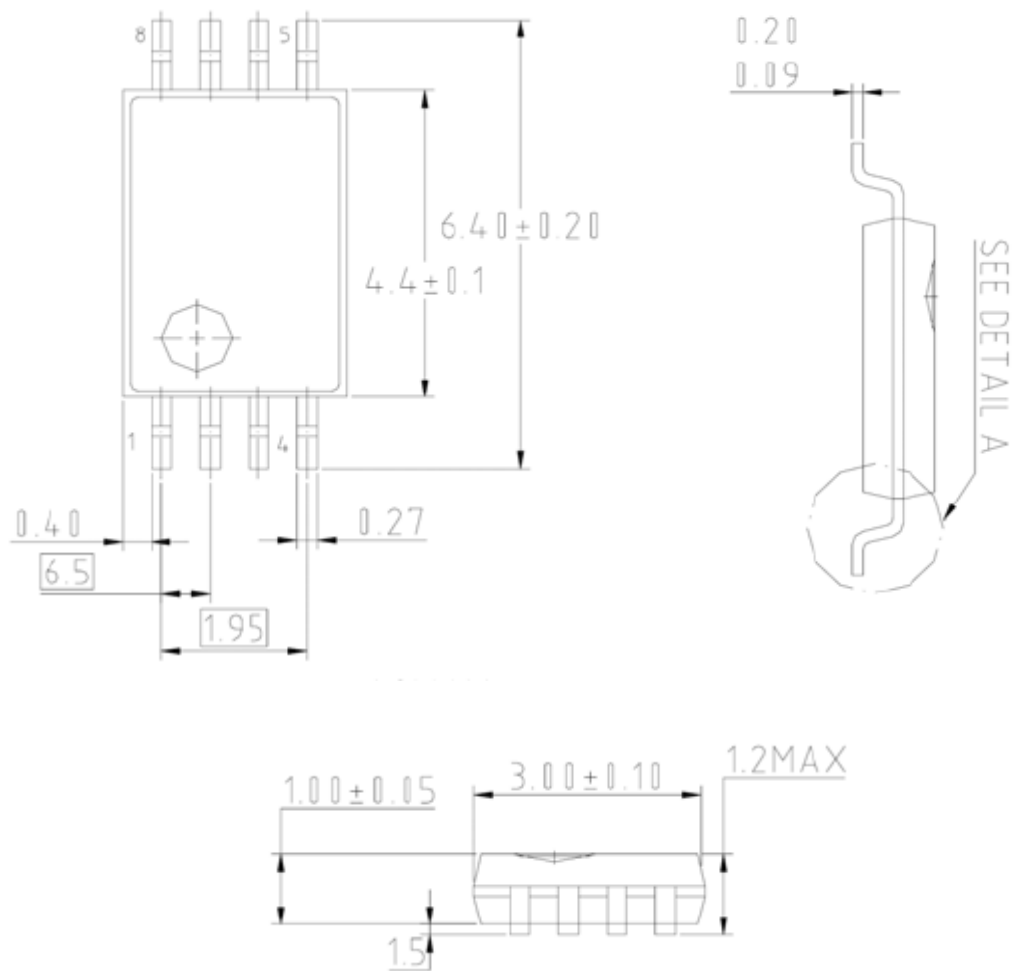


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## Packing Information

### TSSOP-8



Unit: mm

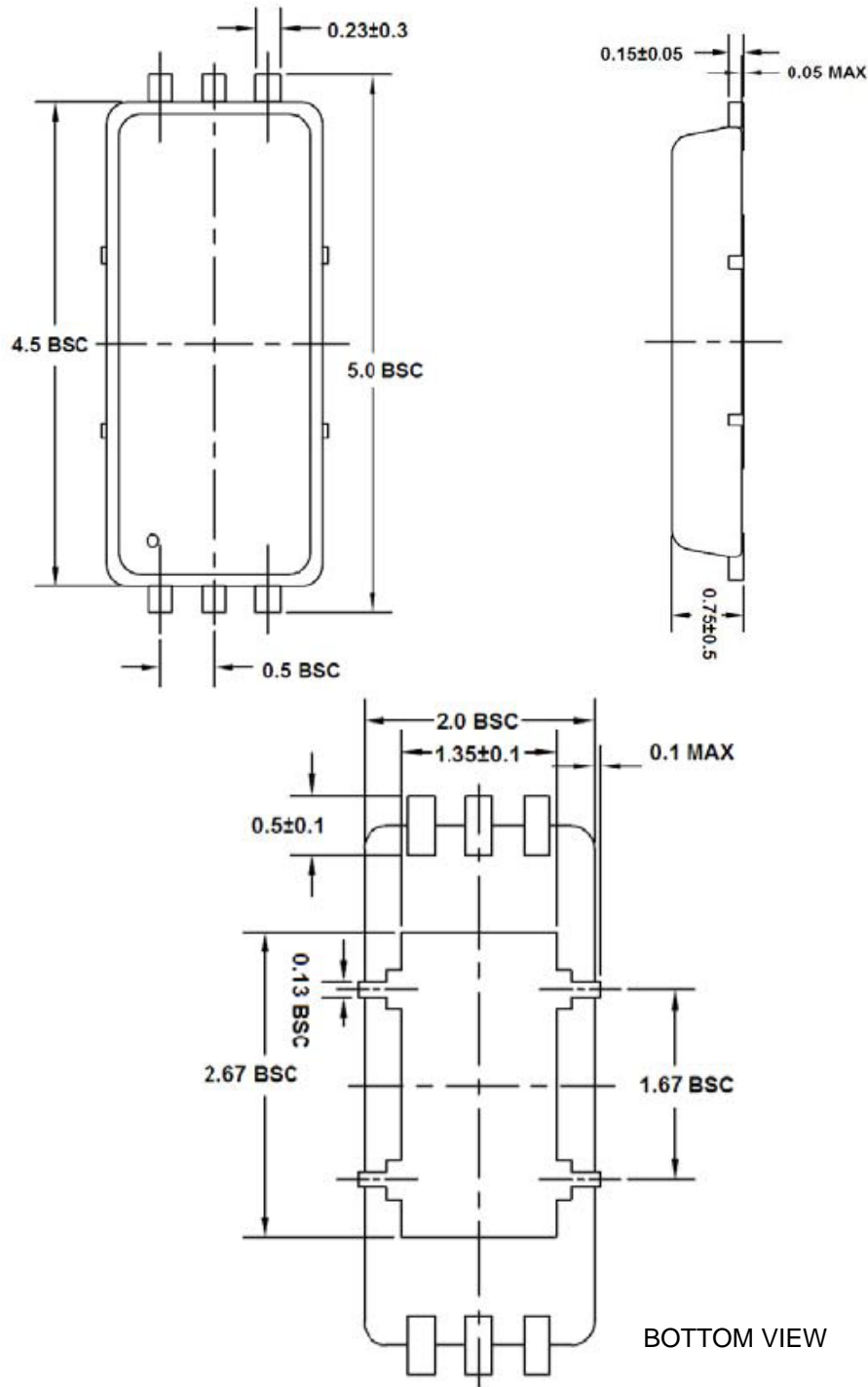


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## Packing Information

### DFN2\*5







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### Notes

ACE does not assume any responsibility for use as critical components in life support devices or systems without the express written approval of the president and general counsel of ACE Electronics Co., LTD. As sued herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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